









First performances of EICROC ASIC to read-out pixelated AC-LGAD sensors for the Electron-Ion Collider (EIC)



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Overview of EICROC

EICROC Characterization via Internal Charge Injection

Initial Testing with Beta Source: PA Measurements

Beta Source testing with Digital readout across all channels

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Roman Pots: Essential for exclusive processes



angles in the beamline, (a) Deep

Virtual Compton Scattering (DVCS)

process.

- Aim is to identify and characterize exclusive, diffractive, and tagged events using detectors integrated with the outgoing hadron beamline, (far-forward detectors).
- Scattered angle < 5 mrad
- To be placed directly in vacuum around the hadron beam to detect intact hadrons with transverse momenta down to a couple hundred MeVs.

Essential Features:

p(p')

- Obtain a position resolution of ~50 μm.
- Time resolution ~30 ps to account for head on collision between the electron and proton beam.

EICROC Project

Design & performance characterization of EICROC2 (32x32) chip intended to readout large surface pixelated AC-LGAD (Simultaneous time and spatial study)

- Design challenge is to fit all the components within a 0.5x0.5 mm²pad.
- Challenge to accommodate for low sensor capacitance (< 1 pF), low electronic noise (~ 1 mV/channel) and jitter to reach the required timing resolutions (20-30 ps),sensitivity to small charges (~ 3 fC) per pixel, and to estimate the amplitude of the central hit pixel for time-walk correction but also of its neighbors (containing the induced cross-talk and charge sharing).
- Achieve good position resolution (~ 20 microns) while ensuring a very low power dissipation, << 1mW/channel.
- Cooling mechanism in vacuum: studies being performed @ IJCLab.
- EICROC0: 1st ASIC prototype has 16 channels

Design Credit for ASIC Development: @ OMEGA withTDC @ CEA/Irfu/DEDIP, ADC @ AGH Krakow.

EICROC0 1st prototype (4x4 pads)



Fig.: EICROC0 Testbench

Fig.: EICROC0 Testboard setup.

EICROC0 chip



Pixel / Channel Mapping	Column 0	Column 1	Column 2	Column 3
Line 0	Pixel (0 ,0)	Pixel (1 ,0)	Pixel (2 ,0)	Pixel (3 ,0)
	#00	#04	#08	#12
Line 1	Pixel (0 ,1)	Pixel (1 ,1)	Pixel (2 ,1)	Pixel (3 ,1)
	#01	#05	#09	#13
Line 2	Pixel (0 ,2)	Pixel (1, 2)	Pixel (2,2)	Pixel (3 ,2)
	#02	#06	#10	#14
Line 3	Pixel (0 ,3)	Pixel (1,3)	Pixel (2,3)	Pixel (3 ,3)
	#03	#07	#11	#15

Fig.: EICROC0 chip channel map.

EICROC0 features

- An analogical fast Transimpedance (TZ) pre-amplifier and a discriminator taken from ALTIROC ASIC design (ATLAS/HGTD).
- 10-bit Time-to-Digital Converter (TDC) measuring the Time-of-Arrival (ToA), designed by CEA/Irfu/DEDIP.
- 8-bit (40 MHz) Analogical-to-Digital Converter (ADC), designed and adapted by AGH University of Science and Technology (Krakow, Poland) from the HGCROC 10 bit ADC.
- Compared to the ALTIROC chip, holding 2 TDCs, one to measure the TOA and the second one associated to the Time-over-Threshold, an ADC has been preferred to measure the signal amplitude to avoid nonlinear behavior of a ToT TDC as a function of injected charge.
- I²C communication (firmware + software developments)
- Digital readout: FIFO depth 8(200ns)
- 5 slow control bytes per pixel:
- ➢ 6 bits local threshold,
- ➢ 6 bits ADC pedestal,
- ➤ 16 TDC calibration bits,
- ➤ several on/off and probes.



EICROC Characterization

Results presented in EIC France 2024 Meeting



- 2. Preamplifier signal divided and sent to $_{\odot}$ ²⁰ Discri/TDC (ToA) and to ADC (measure \check{g}_{15} signal amplitude).
- 3. Digital output data consist of 8 time samples; [TDC, ADC, Hit bit] / time sample for each of the 16 channels.
- 4. Discriminator threshold correction is performed by measuring S-curve, i.e., efficiency as a function of threshold.
- 5. TDC calibration performed.
- 6. TDC is characterized by measuring average 3 time and jitter as a function of injected charge.
- 7. Determination minimum detectable of charge (plotting efficiency as a function of charge).
- 8. ADC waveforms studied with pedestal subtraction.



ADC time sample Fig.: ADC waveform studies for different charge injected.

Pix0

20

15

PA Measurements with ⁹⁰Sr B source



Require a specific firmware

amplitude passes the discriminator threshold). (courtesy: Beng-Yun Ky)

Measurements with ⁹⁰Sr ß source : Digital Readout

Pix-to-Pix Adjustment

- Threshold adjustment channel-by-channel performed.
- Baseline adjustment channel-by-channel done.

EICROC0 + wirebonded BNL AC-LGAD

Detector Bias = -200 V I ~ 0.06 microA

Adjustments performed for lower charge DAC Pulser 12 (~5 fC) [CMD pulse] and setting global threshold 300 DACu



Event Filtering in Digital Readout: Hit Map Evaluation

An event in any pixel is recorded when Discriminator crosses the threshold.
 Event Selection: Hit Map (hit bit = 1) for one of the pixels + same pixel has maximum amplitude recorded after pedestal subtraction.



Condition: Hitbit for Pix 5=1 and Pix 5 with Max Amp

- Only 4% of the events remaining after the selection of events with hit bit =1 in pixel
 5 and has max amplitude.
- ➢ With this condition the first neighbors having hit bit = 1 ~ 6%. (Clearly we need more statistics)
- The far neighbor, almost never crosses the threshold -> The ADC data corresponds to the noise and can be used for pedestal subtraction.

ADC Waveform (Beta Measurements): Pedestal Subtracted

Fig: ADC waveform for each pixel with a condition Pix 5 has hit bit = 1 and max amplitude.

- Code adapted to select events with specific channel with a hit bit = 1 and same channel has maximum amplitude. No condition on the rest of the channels.
- Pedestal Subtraction for ADC performed using a Pix far from the hit pixel on event-by-event basis.
- Clearly, we start to see maxima in each pixel
 ->ADC waveform is dominated by the noise that can be subtracted using a far pixel.



Energy spectrum : After Pedestal Subtracted

(1DACu = 5 mV)



The Width of the spectrum is reduced for pixels away from the hit pixel.

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ADC vs ADC (Correlation study between different neighbors)

Pixel / Channel Mapping	Column 0	Column 1	Column 2	Column 3
Line 0	Pixel (0 ,0)	Pixel (1 ,0)	Pixel (2 ,0)	Pixel (3 ,0)
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Line 2	Pixel (0 ,2)	Pixel (1 ,2)	Pixel (2 ,2)	Pixel (3 ,2)
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Line 3	Pixel (0 ,3)	Pixel (1,3)	Pixel (2,3)	Pixel (3 ,3)
	#03	#07	#11	#15

Fig.: Channel Map. Selected Hit Pix #05 represented in red rectangle. The neighboring pixels selected for correlation study in this slide are represented in blue rectangle.

ADC vs ADC (Correlation study between different neighbors)

Pix 4 vs Pix 5 (I neighbor)

ADC vs ADC for hit pixel = 5 and maximum Amplitude



Pixel / Channel Mapping	Column 0	Column 1	Column 2	Column 3
Line 0	Pixel (0 ,0)	Pixel (1 ,0)	Pixel (2 ,0)	Pixel (3 ,0)
	#00	#04	#08	#12
Line 1	Pixel (0 ,1) #01	Pixel (1,1)	Pixel (2 ,1) #09	Pixel (3 ,1) #13
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Fig.: Channel Map. Selected Hit Pix #05 represented in red rectangle.The neighboring pixels selected for correlation study in this slide are represented in blue rectangle.

ADC vs ADC (Correlation study between different neighbors)



Fig.: ADC 4 vs ADC 5 for hit in Pix 05.



Fig.: Channel Map. Selected Hit Pix #05 represented in red rectangle. The neighboring pixels selected for correlation study in this slide are represented in blue rectangle.



Fig.: ADC 3 vs ADC 5 for hit in Pix 05.

ADC value Pix 5 (DACu)

- The results appear consistent with the scope data.
- The correlations are neighbor order dependent, i.e., first neighbor shows clear correlations with hit pixel. 14

Normalized ADC spectrum w.r.t. hit pixel 5



#The first neighbors show more tailing, and it reduces for pixels away from the hit pixel..

Charge sharing using MPV from Landau Fit

- > Event Selection: Hitbit for Pix 5=1 and Pix 5 with Max Amp after Pedestal subtraction.
- > Landau Fitting to ADC distribution Normalized w.r.t. amplitude in Pix #05.



Fig.: Landau Fit to Normalized ADC distribution for hit in Pix 05. Fit is represented in red color.

Comparison between Pix0, Pix5 and Pix9 as hit pixels



- For central hit pixel Charge sharing is ~23 % for I neighbors ~ 16% for I diagonal neighbors. For edge hit pixel Charge sharing is ~32 % for I neighbors.
- For all cases, diagonals have approximately 60 % of the charge sharing as compared it direct neighbor, as expected.

Conclusions

- ✓ Beta source measurements performed with BNL 4x4 pixelated sensor Wire-Bonded to EICROC0 ASIC.
- \checkmark 95 % of the events are cut with event selection cut (hit bit =1 in pixel of interest and has max amplitude).
- ✓ For pedestal subtraction, the far pixel chosen, which almost never crosses the threshold (implying corresponds to the noise).
- \checkmark The analysis shows consistency with the scope data, while the method is more reliable.
- ✓ Charge sharing studied using Landau fitting.
- ✓ For central hit pixel Charge sharing is ~23 % for first neighbors ~ 16% for first diagonal neighbors. For edge hit pixel Charge sharing is ~32 % for first neighbors ~ 20 % for first diagonal neighbors.
- ✓ For all cases, diagonals have approximately 60 % of the charge sharing as compared to direct neighbor.

Future perspectives

- > Further analysis Ongoing to determine charge sharing in all pixels and timing resolution.
- > Ongoing measurements to acquire data for more statistics.
- Exhaustive study of all the sensor boards (BNL Flip Chip + BNL and HPK Wire-Bonded). (Future: Flip Chip Sensor without metallization for LASER setup)
- > LASER setup completed; measurements commenced to investigate detector position and timing resolution.

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